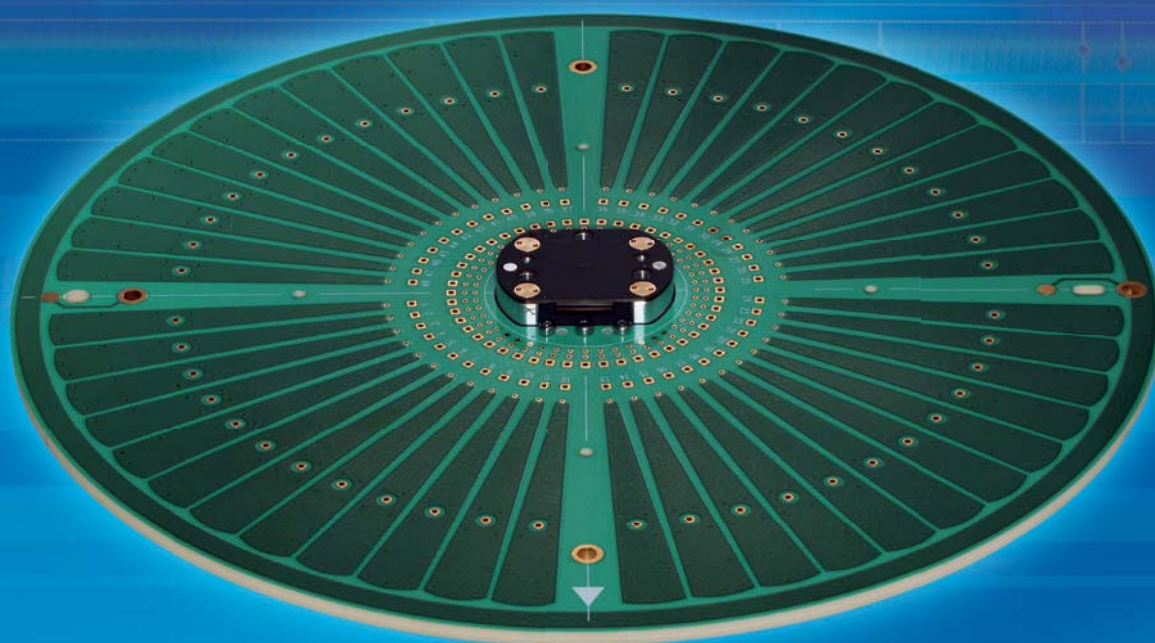


ViProbe[®] Parametric Test Series

Probe Cards for Wafer Test



FEINMETALL

Contact technologies for electronics

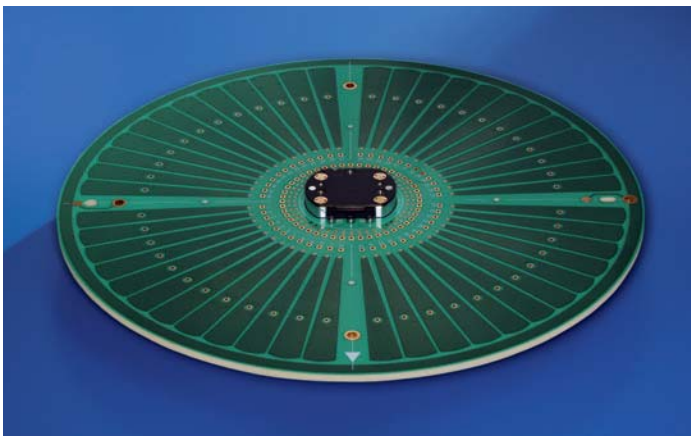


ViProbe® Parametric Test Series

The ViProbe® Parametric Test Series is a vertical probe card for low leakage applications. The advantages are low cost of ownership, easy exchange of needles, precise alignment over the entire lifetime, flexible probe tip depth.

ViProbe® Parametric Test is based on Wired Version Technology.

This product provides the capability for substantial time- and cost- savings in parametric testing.



7 good reasons for using ViProbe® Parametric Test the Vertical Probe Card Technology from Feinmetall

- Low cost of ownership
- Easy Maintenance & Service
- Easy exchange of needles
- Precise alignment over the entire lifetime
- Fast lead time
- Excellent temperature behaviour
- Tolerates changing planarity conditions

FEINMETALL GMBH | HERRENBERG, GERMANY

+49 7032 2001 0 | info@feinmetall.com

FEINMETALL SINGAPORE PTE LTD | SINGAPORE

+65 6316 4544 | info@sg.feinmetall.com

FEINMETALL-OCT | HSINCHU COUNTY, TAIWAN

+886 3 597 22 88 | info@tw.feinmetall.com

FEINMETALL USA LLC | SAN JOSE, USA

+1 408 432 7500 | info.us@feinmetall.com

www.feinmetall.com

Key Parameters P41

Tester:	Agilent 407x series Agilent 408xseries Keithley
Leakage:	< 1pA
Pad Size:	min 30x30µm
Pitch:	min 75µm
Temperature:	-40°C...+180°C

Subject to change without notice

Release April 2011

